

Notice of References Cited	Application/Control No. 10/029,021	Applicant(s)/Patent Under Reexamination AHMAD ET AL.	
	Examiner Saif A. Alhija	Art Unit 2128	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,251,135	10-1993	Serizawa et al.	701/42
*	C	US-5,415,633	05-1995	Lazarus et al.	604/95.05
*	D	US-6,532,833	03-2003	Lec, Ryszard Marian	73/862.338
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*	I	US-3,165,942	01-1965	GEORGE STEINER; et. al.	74/493
*	J	US-5,347,458	09-1994	Serizawa et al.	701/41
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NON-PATENT DOCUMENTS

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	U	"Piezoelectric Ceramics Characterization", T.L. Jordan, NASA Langley Research Center, Hampton, Virginia. Z. Ounaies, ICASE, Hampton, Virginia. September 2001.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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